

# RELIABILITY MONITOR REPORT FOR

## MFN SiGe HBT 0.5µm CMOS (GST40)

## **MAXIM INTEGRATED**

160 RIO ROBLES SAN JOSE, CA 95134

This Report was prepared by MAXIM INTEGRATED Reliability Engineering

### **Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3815CCM MAX3815CCM+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 13177 QUANTITY: 93 FAILS: 0 FITS: 8.7

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2014 and 3/31/2015.

#### **Process Information:**

Process Description: MFN SiGe HBT 0.5µm CMOS (GST40)

Process Description	on:	MFN SIGE HBT 0.5µm CMOS (GST40)						
OPERATING LIFE								
DESCRIPTION		TEST VEHICLE	CONDITION	REAL	OPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1432	MAX3815CCM	135°C	500	HRS	47	0	NXQ0AA250R1
HIGH TEMP OP LIFE	1432	MAX3815CCM+	135°C	1000	HRS	46	0	NXQ0AA250R1
					To	tal:	0	
TEMPERATURE CYC	LE							
DESCRIPTION		TEST VEHICLE	CONDITION	REAL	OPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1432	MAX3815CCM+	-65C TO +150C (Condition C)	200	CYS	99	0	NXQ0AA250R1
TEMP CYCLE, 5' RAMP, 10' DWELL	1432	MAX3815CCM+	-65C TO +150C (Condition C)	1000	CYS	99	0	NXQ0AA250R1
				Total:		tal:	0	
TEMPERATURE HUM	IIDITY E	BIAS						
DESCRIPTION		TEST VEHICLE	CONDITION	REAL	OPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1432	MAX3815CCM+	130C, 85% R.H.	96	HRS	46	0	NXQ0AA250R1
					To	tal:	0	
UNBIASED MOISTUR	E RESI	STANCE						
DESCRIPTION		TEST VEHICLE	CONDITION	REAL	OPOINT	QUANTITY	FAILS	LOT NO.
MOISTURE SOAK	1432	MAX3815CCM+	130C, 85% R.H.	96	HRS	200	0	NXQ0AA250R1
					Total:		0	
FAILURE RATE:	MTTF	(YRS): 13177	<b>QUANTITY: 93</b>		FAILS: 0		FITS: 8.7	